

Programme

Opening and Welcome (9h00), Thomas Zimmer, University of Bordeaux

Session 1: Physics based device simulation (9h15-10h45)

Christoph Jungemann, RWTH Aachen University

Coffee Break: 10h45-11h00

Session 2: Safe operating limits of SiGe-THz devices (11h00-12h30)

Anjan Chakravorty, IIT Madras, India, now guest professor at the University of Bordeaux

Lunch Break: 12h30-14h00

Session 3: Reliability of SiGe-THz devices (14h00-15h30)

Grazia Sasso, University of Naples, Italy

Coffee Break: 15h30-15h45

Session 4: Reliability aware circuit design (15h45-17h15)

Cristell Maneux, University of Bordeaux, France

17h30: End of SiGe-THz device Tutorial